



# Wire Wound Type Common Mode Filter

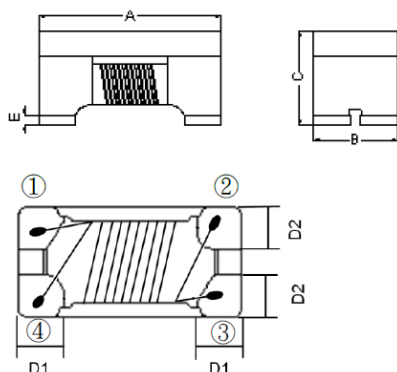
WCM3216F2SV-SERIES

## 1. Features

1. High common mode impedance at high frequency cause excellent noise suppression performance.
2. WCM3216F2SV series realizes small size and low profile. 3.2x1.6x2.0 mm.
3. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
4. High reliability -Reliability test complied to AEC-Q200



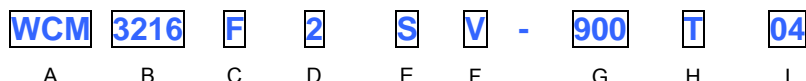
## 2. Dimension



Series	A(mm)	B(mm)	C(mm)	D1(mm)	D2(mm)	E(mm)
3216F2SV	3.2±0.2	1.6±0.2	2.0±0.2	0.65±0.1	0.64±0.1	0.15±0.1

Units: mm

## 3. Part Numbering

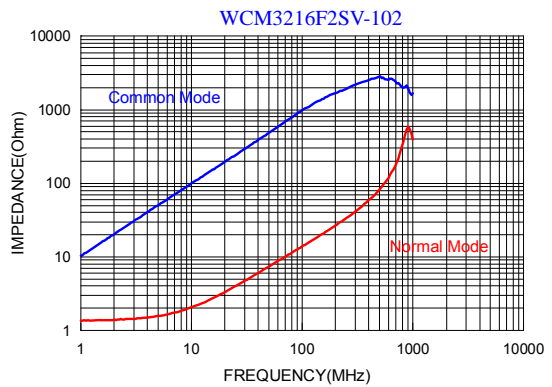
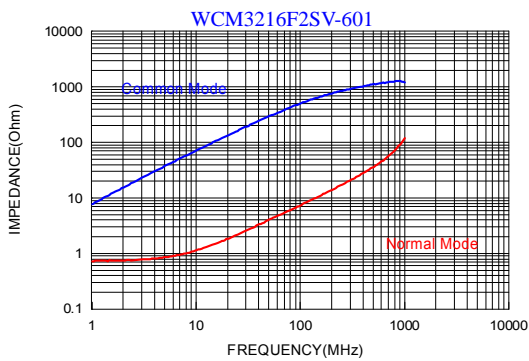
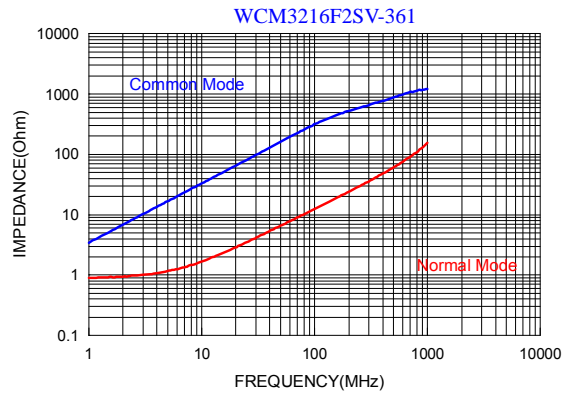
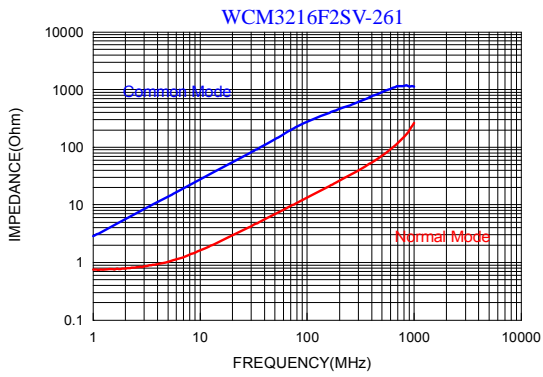
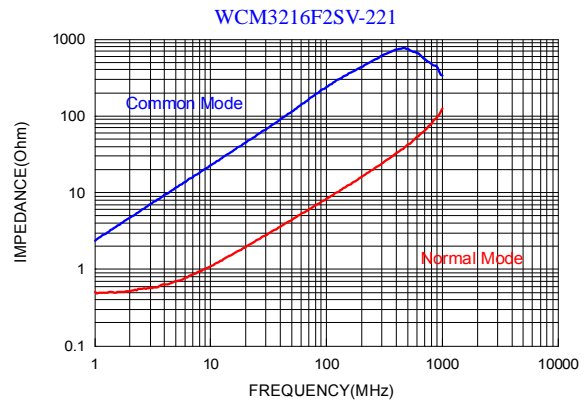
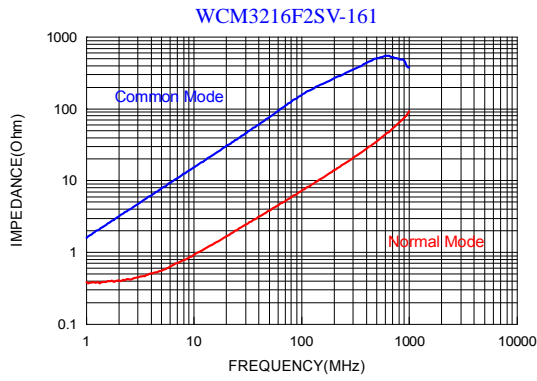
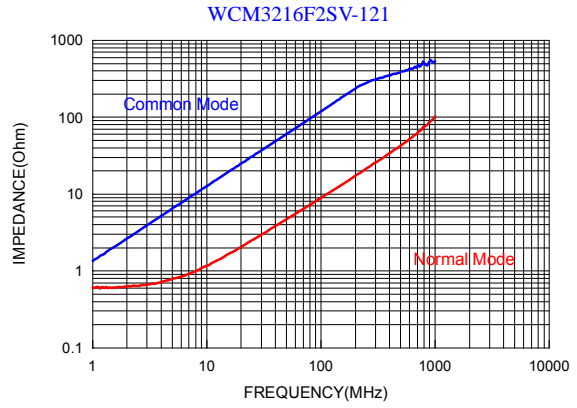
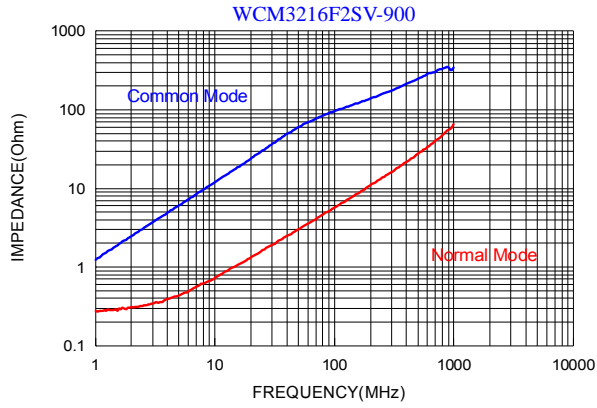


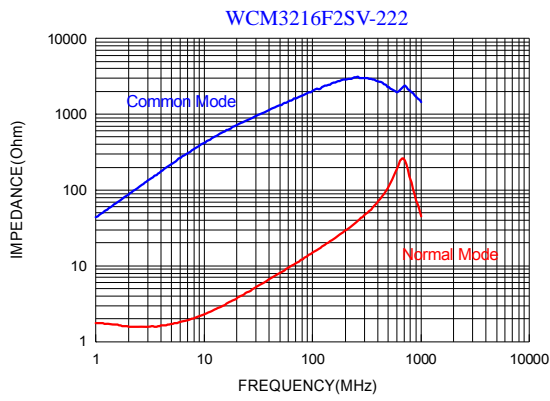
- A: Series  
 B: Dimension  
 C: Material                      Ferrite Core  
 D: Number of Lines        2=2 lines  
 E: Type                            S=Shielded , N=Unshielded  
 F: Category Code            V=Vehicle  
 G: Impedance                 900=90Ω  
 H: Packaging                    T=Taping and Reel  
 I: Rated Current              04=400mA

## 4. Specification

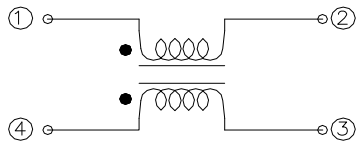
TAI-TECH Part Number	Common mode Impedance (Ω)	Test Frequency (MHz)	DC Resistance (Ω) max.	Rated Current (mA)max.	Rated Volt. (Vdc)max.	Withstand Volt. (Vdc) Max.	IR (Ω) min.
WCM3216F2SV-900T04	90±25%	100	0.30	400	50	125	10M
WCM3216F2SV-121T03	120±25%	100	0.30	350	50	125	10M
WCM3216F2SV-161T03	160±25%	100	0.40	350	50	125	10M
WCM3216F2SV-221T03	220±25%	100	0.45	300	50	125	10M
WCM3216F2SV-261T03	260±25%	100	0.50	300	50	125	10M
WCM3216F2SV-361T03	360±25%	100	0.60	300	50	125	10M
WCM3216F2SV-601T03	600±25%	100	0.80	300	50	125	10M
WCM3216F2SV-102T02	1000±25%	100	1.00	200	50	125	10M
WCM3216F2SV-222T02	2200±25%	100	1.20	200	50	125	10M

### Typical Impedance v.s. Frequency Curve



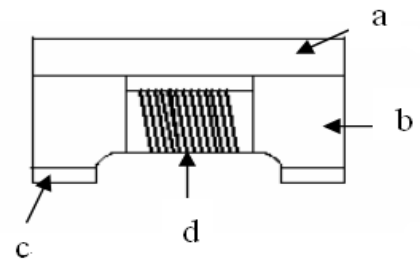


### 5. Schematic Diagram



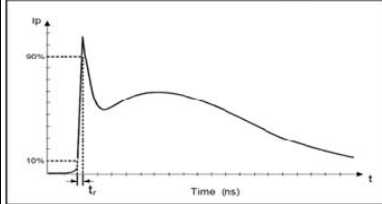
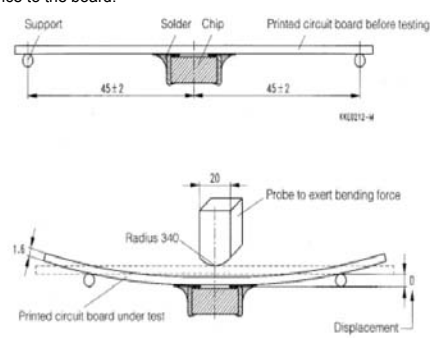
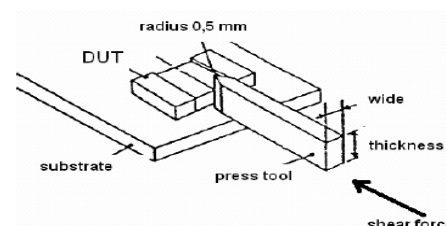
### 6. Materials

No.	Description	Specification
a.	Upper Plate	Ferrite
b.	Core	Ferrite Core
c.	Termination	Tin (Pb Free)
d.	Wire	Enameled Copper Wire



### 7. Reliability and Test Condition

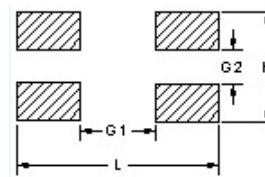
Item	Performance	Test Condition															
Operating temperature	-55~+125°C (Including self - temperature rise)																
Storage temperature and Humidity range	-55~+125°C (on board)																
<b>Electrical Performance Test</b>																	
Z(common mode)	Refer to standard electrical characteristics list.	Agilent-4291A+ Agilent -16197A															
DCR		Agilent-4338B															
I.R.		Agilent4339															
Temperature Rise Test	Rated Current < 1A ΔT 20°C Max Rated Current ≥ 1A ΔT 40°C Max	1.Applied the allowed DC current. 2.Temperature measured by digital surface thermometer															
<b>Reliability Test</b>																	
High Temperature Exposure(Storage) AEC-Q200	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Temperature : 125±2°C Duration : 1000hrs Min. Measured at room temperature after placing for 24±2 hrs															
Temperature Cycling AEC-Q200		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1 : -55±2°C 30min Min. Step2 : 125±2°C transition time 1min MAX. Step3 : 125±2°C 30min Min. Step4 : Low temp. transition time 1min MAX. Number of cycles : 1000 Measured at room temperature after placing for 24±2 hrs															
Moisture Resistance		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles 1.Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs. 2.Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs. 3.Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs,keep at 25°C for 2hrs then keep at -10°C for 3hrs 4.Keep at 25°C 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.															
Biased Humidity (AEC-Q200)		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity : 85±3%RH, Temperature : 85°C±2°C Duration : 1000hrs Min with 100% rated current. Measured at room temperature after placing for24±2hrs															
High Temperature Operational Life (AEC-Q200)		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Temperature : 125±2°C Duration : 1000hrs Min. with 100% rated current. Measured at room temperature after placing for24±2hrs															
External Visual		Appearance : No damage.	Inspect device construction, marking and workmanship. Electrical Test not required.														
Physical Dimension	According to the product specification size measurement	According to the product specification size measurement															
Resistance to Solvents	Appearance : No damage.	Add aqueous wash chemical - OKEM clean or equivalent.															
Mechanical Shock	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	<table border="1"> <thead> <tr> <th>Type</th> <th>Peak value (g's)</th> <th>Normal duration (D) (ms)</th> <th>Wave form</th> <th>Velocity change (Vi)ft/sec</th> </tr> </thead> <tbody> <tr> <td>SMD</td> <td>100</td> <td>6</td> <td>Half-sine</td> <td>12.3</td> </tr> <tr> <td>Lead</td> <td>100</td> <td>6</td> <td>Half-sine</td> <td>12.3</td> </tr> </tbody> </table> <p>shocks in each direction along 3 perpendicular axes.</p>	Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec	SMD	100	6	Half-sine	12.3	Lead	100	6	Half-sine	12.3
Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec													
SMD	100	6	Half-sine	12.3													
Lead	100	6	Half-sine	12.3													

Item	Performance	Test Condition								
Vibration		IPC/JEDEC J-STD-020DClassification Reflow Profiles Oscillation Frequency: 10~2K~10Hz for 20 minute Equipment : Vibration checker Total Amplitude:1.52mm±10% Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations) ◦ Test condition :								
Resistance to Soldering Heat	Appearance : No damage. Impedance : within±15% of initial value Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	<table border="1"> <thead> <tr> <th>Temperature(°C)</th> <th>Time(s)</th> <th>Temperature ramp/immersion and emersion rate</th> <th>Number of heat cycles</th> </tr> </thead> <tbody> <tr> <td>260±5(soldertemp)</td> <td>10±1</td> <td>25mm/s ±6 mm/s</td> <td>1</td> </tr> </tbody> </table>	Temperature(°C)	Time(s)	Temperature ramp/immersion and emersion rate	Number of heat cycles	260±5(soldertemp)	10±1	25mm/s ±6 mm/s	1
Temperature(°C)	Time(s)	Temperature ramp/immersion and emersion rate	Number of heat cycles							
260±5(soldertemp)	10±1	25mm/s ±6 mm/s	1							
Thermal shock (AEC-Q200)		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1 : -55±2°C 15±1min Step2 : 125±2°C within 20Sec. Step3 : 125±2°C 15±1min Number of cycles : 300 Measured at room tempraturc after placing fo24±2hrs								
ESD	Appearance : No damage.									
Solderability	More than 95% of the terminal electrode should be covered with solder ◦	Steam Aging: 8 hours ± 15 min Preheat: 150°C,60sec. Solder: Sn96.5% Ag3% Cu0. 5% Temperature: 245±5°C ◦ Flux for lead free: Rosin. 9.5% ◦ Dip time: 4±1sec. Depth: completely cover the termination								
Electrical Characterization	Refer Specification for Approval	Summary to show Min, Max, Mean and Standard deviation .								
Flammability	Electrical Test not required.	V-0 or V-1 are acceptable.								
Board Flex	Appearance : No damage	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles Place the 100mm X 40mm board into a fixture similar to the one shown in below Figure with the component facing down. The apparatus shall consist of mechanical means to apply a force which will bend the board (D) x = 2 mm minimum. The duration of the applied forces shall be 60 (+ 5) sec. The force is to be applied only once to the board. 								
Terminal Strength(SMD)	Appearance : No damage	AEC-Q200,TAI-TECH SPEC V10N 30 SEC 								

## 8. Soldering and Mounting

### 8-1. Recommended PC Board Pattern

	WCM3216F2S/F2N
L	3.70
H	1.70
G1	2.30
G2	0.70



PC board should be designed so that products can prevent damage from mechanical stress when warping the board. Products shall be positioned in the sideways direction to against the mechanical stress to prevent failure.

### 8-2. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

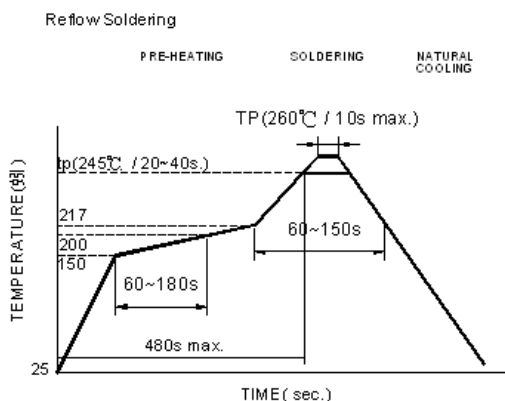
#### 8-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for re-flow soldering in Figure 1.

#### 8-2.2 Soldering Iron(Figure 2):

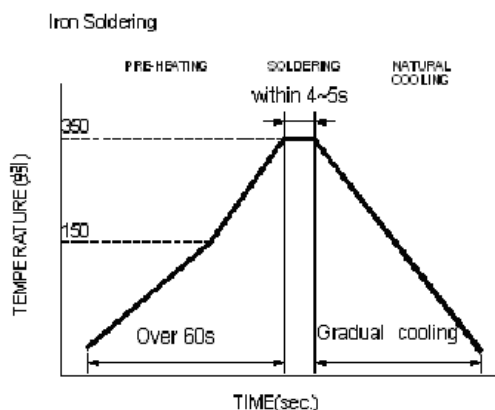
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150°C
- Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- 355°C tip temperature (max)
- 1.0mm tip diameter (max)
- Limit soldering time to 4~5 sec.



Reflow times: 3 times max.

Fig.1



Iron Soldering times: 1 times max.

Fig.2





## 測試報告

## Test Report

號碼(No.) : CE/2018/34305 日期(Date) : 2018/03/22

頁數(Page): 1 of 14

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.

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(中國, 江蘇省, 宿遷市, 泗洪縣, 經濟開發區杭州路南側, 建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)



以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description) : WIREWOUND SERIES  
樣品型號(Style/Item No.) : WCM、WCL、HSF、HDMI、DVI、BCM、PCM、TCM、LCM、LPF、TXF、ACM、DCM、WIH、BPH、TNH、YCM、STF SERIES  
收件日期(Sample Receiving Date) : 2018/03/15  
測試期間(Testing Period) : 2018/03/15 TO 2018/03/22

=====  
測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages).

Troy Chang, Manager - Tech  
Signed for and on behalf of  
SGS TAIWAN LTD.  
Chemical Laboratory - Taipei



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### 測試結果(Test Results)

測試部位(PART NAME)No. 1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5 (2013), 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5 (2013) and performed by ICP-AES.	2	n. d.
鉛 / Lead (Pb)	mg/kg		2	n. d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4 (2013), 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4 (2013) and performed by ICP-AES.	2	n. d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321-7-2 (2017), 以UV-VIS 檢測. / With reference to IEC 62321-7-2 (2017) and performed by UV-VIS.	8	n. d.
<b>多溴聯苯總和 / Sum of PBBs</b>	mg/kg	參考IEC 62321-6 (2015), 以氣相層析/質譜儀檢測. / With reference to IEC 62321-6 (2015) and performed by GC/MS.	-	n. d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n. d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n. d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n. d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	參考IEC 62321-6 (2015), 以氣相層析/質譜儀檢測. / With reference to IEC 62321-6 (2015) and performed by GC/MS.	-	n. d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n. d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n. d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n. d.	
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified ( $\alpha$ -HBCDD, $\beta$ -HBCDD, $\gamma$ -HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321 (2008), 以氣相層析/質譜儀檢測. / With reference to IEC 62321 (2008). Analysis was performed by GC/MS.	5	n. d.
<b>鹵素 / Halogen</b>				
鹵素(氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582 (2016), 以離子層析儀分析. / With reference to BS EN 14582 (2016). Analysis was performed by IC.	50	n. d.
鹵素(氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n. d.
鹵素(溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n. d.
鹵素(碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n. d.

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# 測試報告

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(中國, 江蘇省, 宿遷市, 泗洪縣, 經濟開發區杭州路南側, 建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)



測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No. : 85-68-7)	mg/kg	參考IEC 62321-8 (2017), 以氣相層析儀/質譜儀檢測. / With reference to IEC 62321-8 (2017). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No. : 84-74-2)	mg/kg		50	n. d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No. : 117-81-7)	mg/kg		50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No. : 84-69-5)	mg/kg		50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di-isodecyl phthalate) (CAS No. : 26761-40-0; 68515-49-1)	mg/kg		50	n. d.
鄰苯二甲酸二異壬酯 / DINP (Di-isononyl phthalate) (CAS No. : 28553-12-0; 68515-48-0)	mg/kg		50	n. d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No. : 117-84-0)	mg/kg		50	n. d.
鄰苯二甲酸二正己酯 / DNHP (Di-n-hexyl phthalate) (CAS No. : 84-75-3)	mg/kg		50	n. d.
鄰苯二甲酸二戊酯 / DNPP (Di-n-pentyl phthalate) (CAS No. : 131-18-0)	mg/kg		50	n. d.
銻 / Antimony (Sb)	mg/kg	參考US EPA 3052 (1996), 以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA 3052 (1996). Analysis was performed by ICP-AES.	2	n. d.
鈹 / Beryllium (Be)	mg/kg		2	n. d.

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(中國, 江蘇省, 宿遷市, 泗洪縣, 經濟開發區杭州路南側, 建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)



測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No. 1
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	參考US EPA 3550C (2007), 以液相層析/質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis was performed by LC/MS.	10	n. d.
全氟辛酸 / PFOA (CAS No. : 335-67-1)	mg/kg		10	n. d.
聚氯乙烷 / PVC	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	-	Negative

### 備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n. d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. \*\*= Qualitative analysis (No Unit) 定性分析(無單位)
6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
7. 樣品的測試是基於申請人要求混合測試, 報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

### PFOS參考資訊(Reference Information) : 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm), 在半成品、成品或零部件中不得超過0.1%(1000ppm), 在紡織品或塗層材料中不得超過1µg/m<sup>2</sup>。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above 1µg/m<sup>2</sup>.)

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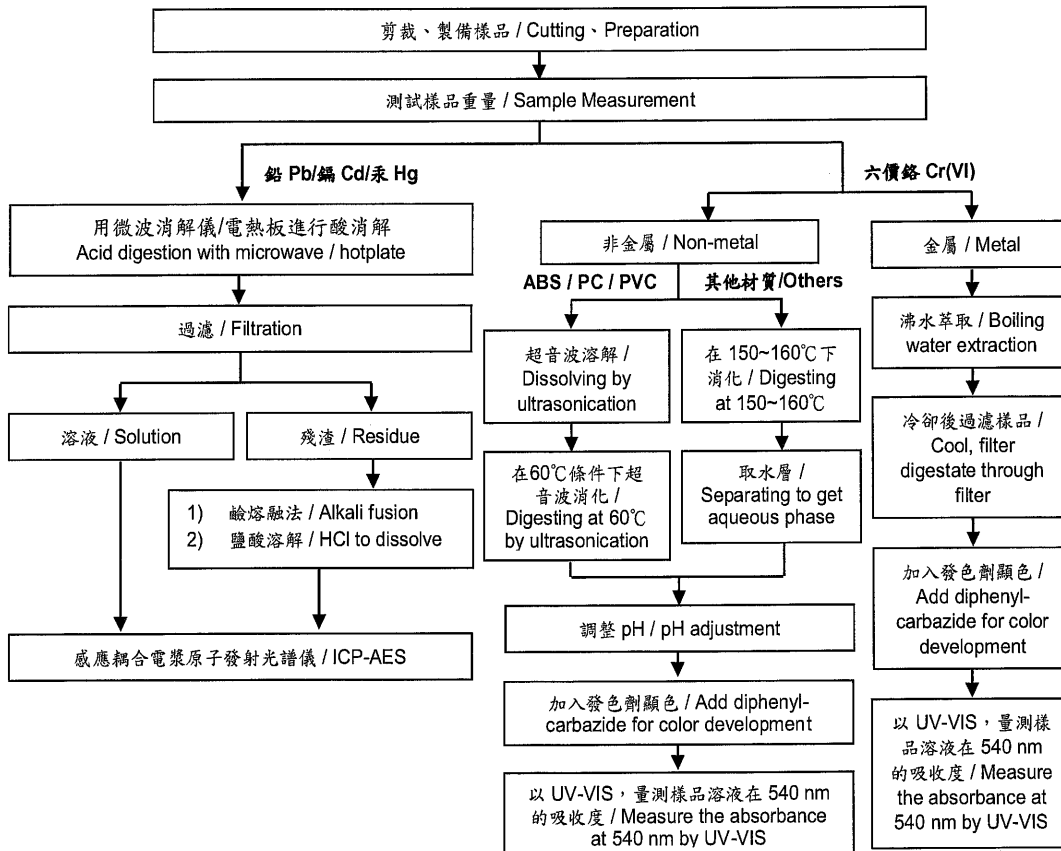
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### 重金屬流程圖 / Analytical flow chart of Heavy Metal

根據以下的流程圖之條件, 樣品已完全溶解。(六價鉻測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>6+</sup> test method excluded)

- 測試人員: 王志瑋 / Technician: JR Wang
- 測試負責人: 張啟興 / Supervisor: Troy Chang



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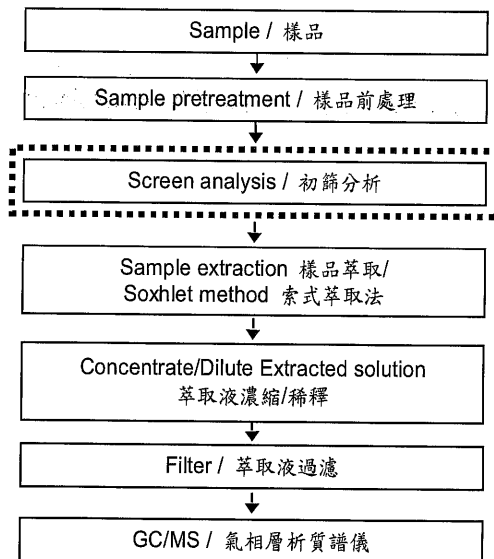
### 多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBB/PBDE

- 測試人員: 涂雅苓 / Technician: Yaling Tu
- 測試負責人: 張啟興 / Supervisor: Troy Chang

初次測試程序 / First testing process ———→

選擇性篩檢程序 / Optional screen process .....→

確認程序 / Confirmation process - - - ->



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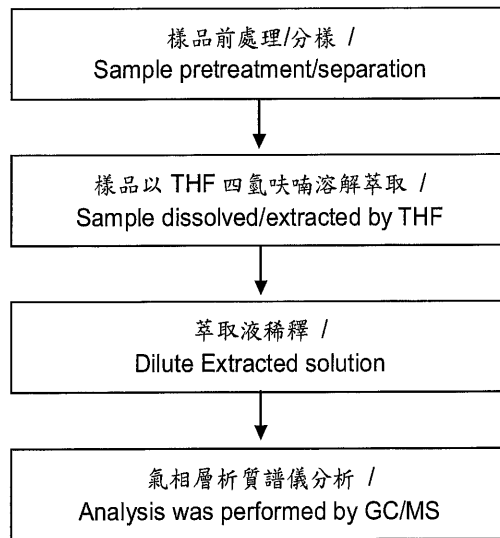
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### 可塑劑分析流程圖 / Analytical flow chart - Phthalate

- 測試人員: 徐毓明 / Technician: Andy Hsu
- 測試負責人: 張啟興 / Supervisor: Troy Chang

#### 【測試方法/Test method: IEC 62321-8】



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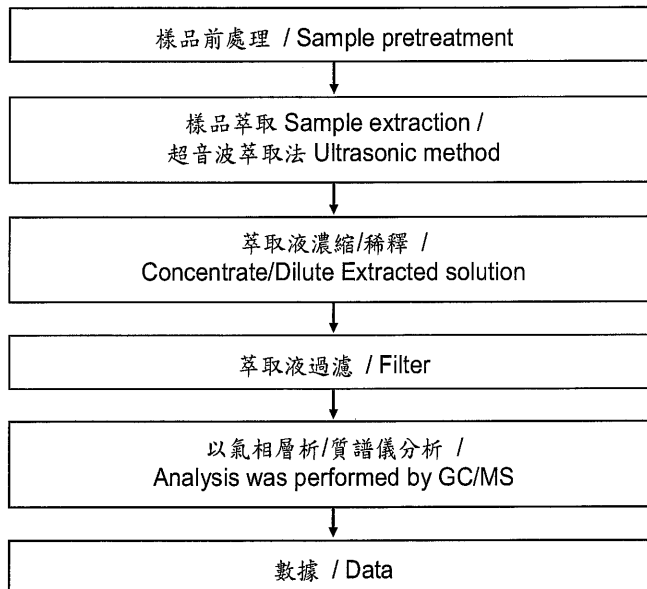
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### 六溴環十二烷分析流程圖 / Analytical flow chart - HBCDD

- 測試人員: 涂雅苓 / Technician: Yaling Tu
- 測試負責人: 張啟興 / Supervisor: Troy Chang



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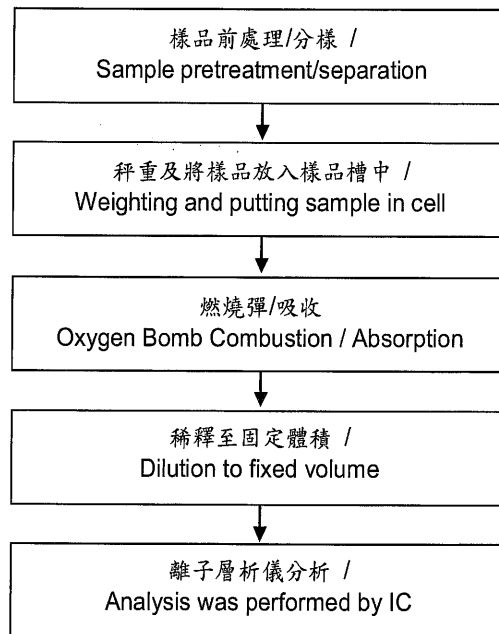
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### 鹵素分析流程圖 / Analytical flow chart - Halogen

- 測試人員: 陳思臻 / Technician: Rita Chen
- 測試負責人: 張啟興 / Supervisor: Troy Chang



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# 測試報告

## Test Report

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(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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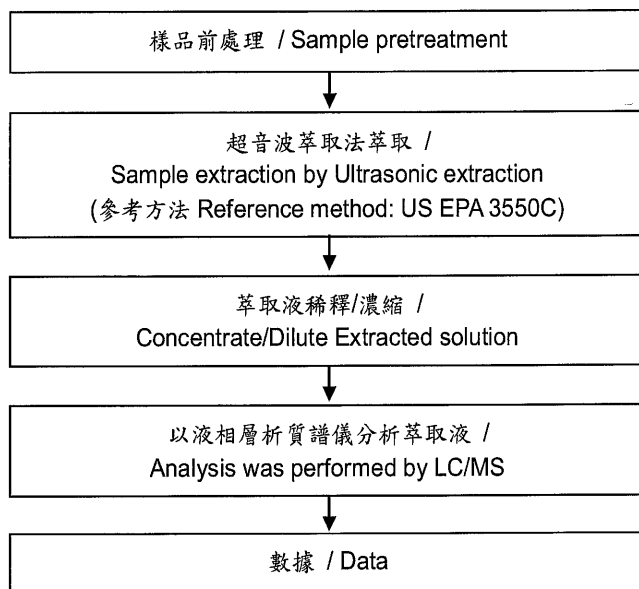
(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

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### 全氟辛酸/全氟辛烷磺酸分析流程圖 / Analytical flow chart - PFOA/PFOS

- 測試人員：涂雅苓 / Technician: Yaling Tu
- 測試負責人：張啟興 / Supervisor: Troy Chang



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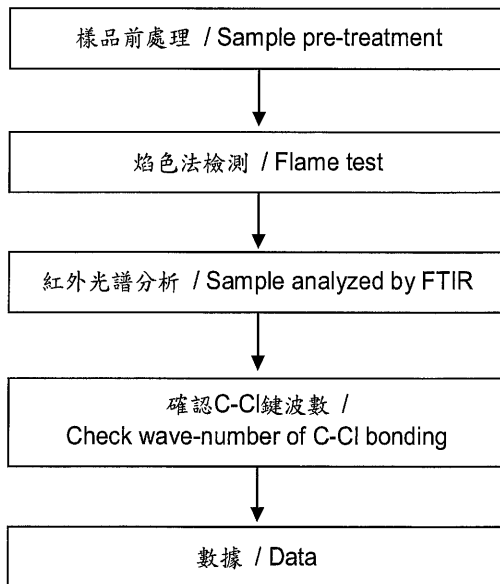
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### 聚氯乙烯物質判定分析流程圖 / Analysis flow chart - PVC

- 測試人員: 涂雅苓 / Technician: Yaling Tu
- 測試負責人: 張啟興 / Supervisor: Troy Chang



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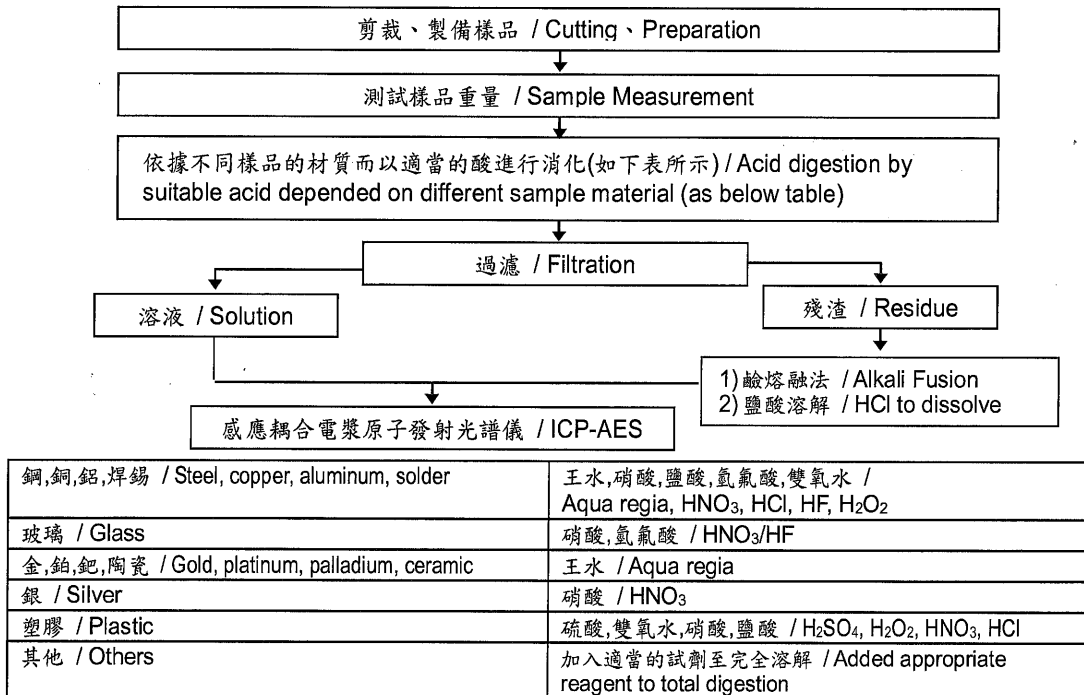
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根據以下的流程圖之條件, 樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.

- 測試人員: 王志瑋 / Technician: JR Wang
- 測試負責人: 張啟興 / Supervisor: Troy Chang

### 元素以 ICP-AES 分析的消化流程圖 (Flow Chart of digestion for the elements analysis performed by ICP-AES)



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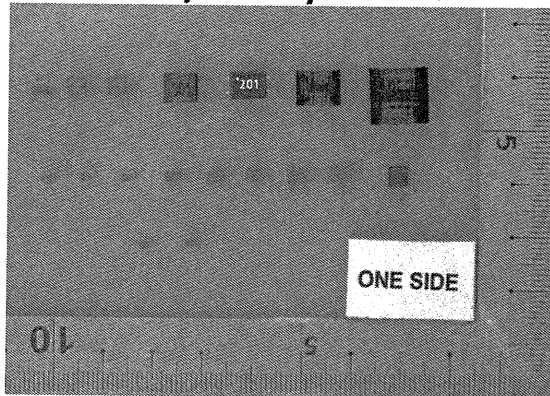
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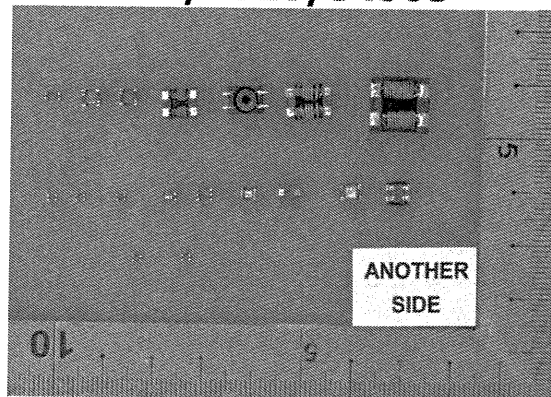
\* 照片中如有箭頭標示, 則表示為實際檢測之樣品/部位. \*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

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### CE/2018/34305



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